

STD7N80K5, STP7N80K5, STU7N80K5

N-channel 800 V, 0.95 Ω typ., 6 A Zener-protected SuperMESHTM 5 Power MOSFETs in DPAK, TO-220 and IPAK packages

Datasheet - production data

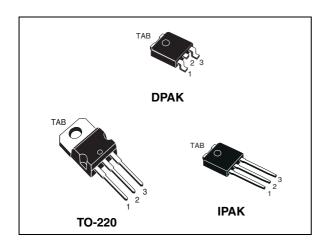
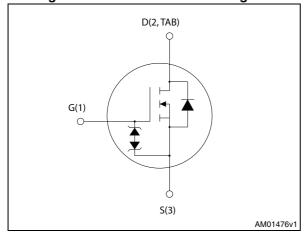


Figure 1. Internal schematic diagram



Features

Order codes	V _{DS}	R _{DS(on)} max	I _D	P _{TOT}
STD7N80K5				
STP7N80K5	800 V	1.2 Ω	6 A	110 W
STU7N80K5				

- Worldwide best FOM (figure of merit)
- Ultra low gate charge
- 100% avalanche tested
- Zener-protected

Applications

· Switching applications

Description

These N-channel Zener-protected Power MOSFETs are designed using ST's revolutionary avalanche-rugged very high voltage SuperMESH™ 5 technology, based on an innovative proprietary vertical structure. The result is a dramatic reduction in on-resistance, and ultra-low gate charge for applications which require superior power density and high efficiency.

Table 1. Device summary

Order codes	Marking	Package	Packaging
STD7N80K5		DPAK	Tape and reel
STP7N80K5	7N80K5	TO-220	Tube
STU7N80K5		IPAK	rube

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1 Electrical ratings

Table 2. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V _{GS}	Gate- source voltage	± 30	V
I _D	Drain current (continuous) at T _C = 25 °C	6	Α
I _D	Drain current (continuous) at T _C = 100 °C	3.8	Α
I _{DM} ⁽¹⁾	Drain current (pulsed)	24	Α
P _{TOT}	Total dissipation at T _C = 25 °C	110	W
I _{AR}	Max current during repetitive or single pulse avalanche (pulse width limited by T _{jmax})	2	А
E _{AS}	Single pulse avalanche energy (starting $T_J = 25$ °C, $I_D = I_{AS}$, $V_{DD} = 50$ V)	88	mJ
dv/dt (2)	Peak diode recovery voltage slope	4.5	V/ns
T _j	Operating junction temperature		°C
T _{stg}	Storage temperature	-55 to 150	°C

^{1.} Pulse width limited by safe operating area.

Table 3. Thermal data

Symbol	Parameter		Unit		
Symbol	raiametei	DPAK	TO-220	IPAK	Oille
R _{thj-case}	Thermal resistance junction-case max		1.14		°C/W
R _{thj-amb}	Thermal resistance junction-amb max		62.5	100	°C/W
R _{thj-pcb} ⁽¹⁾	Thermal resistance junction-pcb max	50			°C/W

^{1.} When mounted on 1 inch² FR-4, 2 Oz copper board.

^{2.} $I_{SD} \leq$ 6 A, di/dt \leq 100 A/ μ s, $V_{DS(peak)} \leq V_{(BR)DSS}$

2 Electrical characteristics

(T_{CASE} = 25 °C unless otherwise specified).

Table 4. On/off states

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage (V _{GS} = 0)	I _D = 1 mA	800			V
I _{DSS}	Zero gate voltage drain current (V _{GS} = 0)	V _{DS} = 800 V V _{DS} = 800 V, Tc=125 °C			1 50	μA μA
I _{GSS}	Gate body leakage current (V _{DS} = 0)	V _{GS} = ± 20 V			±10	μΑ
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}, I_{D} = 100 \mu A$	3	4	5	٧
R _{DS(on)}	Static drain-source on- resistance	V _{GS} = 10 V, I _D = 3 A		0.95	1.2	Ω

Table 5. Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
C _{iss}	Input capacitance		-	360	-	pF
C _{oss}	Output capacitance	V _{DS} =100 V, f=1 MHz, V _{GS} =0	-	30	-	pF
C _{rss}	Reverse transfer capacitance	20 7 20	-	1	-	pF
C _{o(tr)} ⁽¹⁾	Equivalent capacitance time related	$V_{GS} = 0$, $V_{DS} = 0$ to 640 V	-	47	-	pF
C _{o(er)} ⁽²⁾	Equivalent capacitance energy related		-	20	-	pF
R _G	Intrinsic gate resistance	f = 1 MHz, I _D =0	-	6	-	Ω
Qg	Total gate charge	V_{DD} = 640 V, I_D = 6 A V_{GS} =10 V (see Figure 17)	-	13.4	-	nC
Q _{gs}	Gate-source charge		ı	3.7	-	nC
Q_{gd}	Gate-drain charge		-	7.5	-	nC

^{1.} Time related is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}

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^{2.} Energy related is defined as a constant equivalent capacitance giving the same stored energy as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}

Table 6. Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t _{d(on)}	Turn-on delay time	$V_{DD} = 400 \text{ V}, I_{D} = 3 \text{ A},$ $R_{G} = 4.7 \Omega, V_{GS} = 10 \text{ V}$ (see Figure 19)	-	11.3	-	ns
t _r	Rise time			8.3		ns
t _{d(off)}	Turn-off delay time			23.7		ns
t _f	Fall time			20.2		ns

Table 7. Source drain diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I _{SD}	Source-drain current		-		6	Α
I _{SDM}	Source-drain current (pulsed)		-		24	Α
V _{SD} ⁽¹⁾	Forward on voltage	I _{SD} = 6 A, V _{GS} =0	-		1.5	V
t _{rr}	Reverse recovery time	I _{SD} = 6 A, V _{DD} = 60 V	-	315		ns
Q _{rr}	Reverse recovery charge	$di/dt = 100 A/\mu s$,	-	2.8		μC
I _{RRM}	Reverse recovery current	(see Figure 18)	-	17.5		Α
t _{rr}	Reverse recovery time	I _{SD} = 6 A,V _{DD} = 60 V di/dt=100 A/μs, Tj=150 °C (see Figure 18)	-	480		ns
Q _{rr}	Reverse recovery charge		-	3.8		μC
I _{RRM}	Reverse recovery current		-	16		Α

^{1.} Pulsed: pulse duration = $300\mu s$, duty cycle 1.5%

Table 8. Gate-source Zener diode

Symbol	Parameter	Test conditions	Min	Тур.	Max	Unit
V _{(BR)GSO}	Gate-source breakdown voltage	I_{GS} = ± 1mA, I_{D} =0	30	1	1	V

The built-in back-to-back Zener diodes have been specifically designed to enhance not only the device's ESD capability, but also to make them capable of safely absorbing any voltage transients that may occasionally be applied from gate to source. In this respect, the Zener voltage is appropriate to achieve efficient and cost-effective protection of device integrity. The integrated Zener diodes thus eliminate the need for external components.



2.1 Electrical characteristics (curves)

Figure 2. Safe operating area for DPAK and IPAK

Figure 3. Thermal impedance for DPAK and IPAK

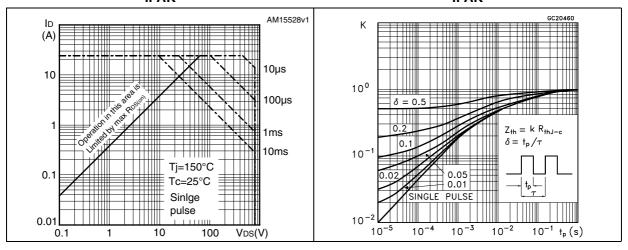


Figure 4. Safe operating area for TO-220

Figure 5. Thermal impedance for TO-220

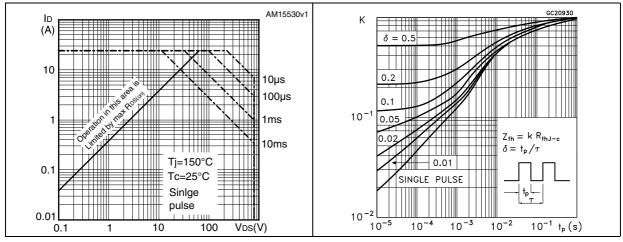
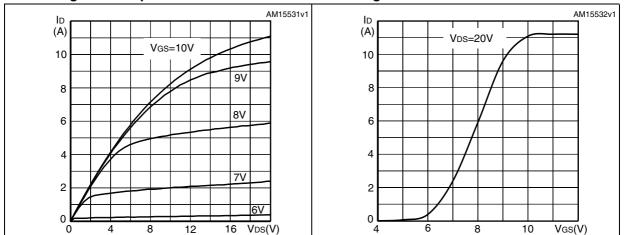


Figure 6. Output characteristics

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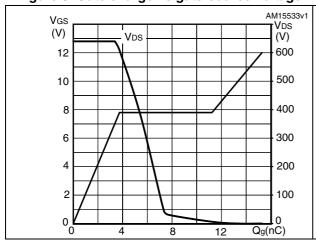
Figure 7. Transfer characteristics



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Figure 8. Gate charge vs gate-source voltage

Figure 9. Static drain-source on-resistance



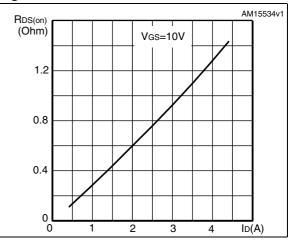
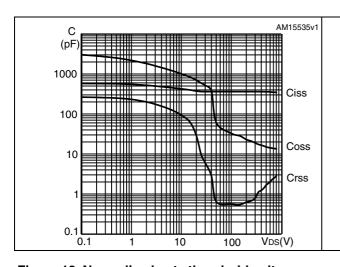


Figure 10. Capacitance variations

Figure 11. Source-drain diode forward characteristics



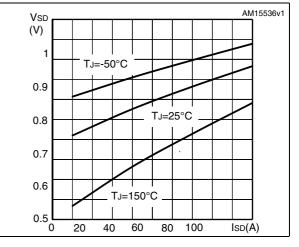
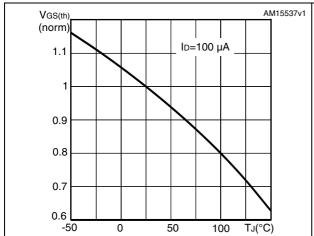


Figure 12. Normalized gate threshold voltage vs temperature

Figure 13. Normalized on-resistance vs temperature



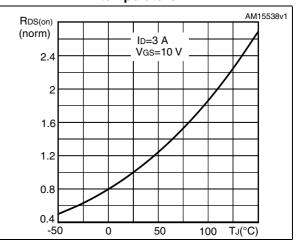
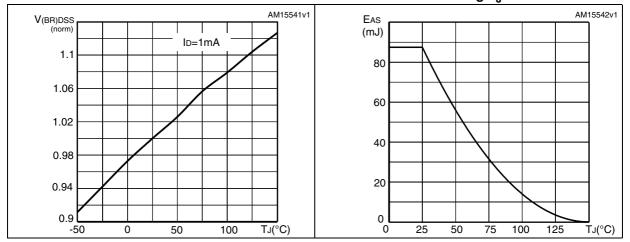


Figure 14. Normalized $V_{(BR)DSS}$ vs temperature

Figure 15. Maximum avalanche energy vs starting $\mathbf{T}_{\mathbf{J}}$



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3 Test circuits

Figure 16. Switching times test circuit for resistive load

Figure 17. Gate charge test circuit

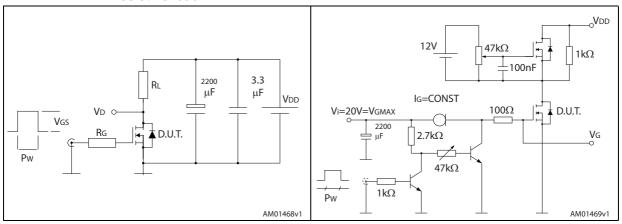


Figure 18. Test circuit for inductive load switching and diode recovery times

Figure 19. Unclamped inductive load test circuit

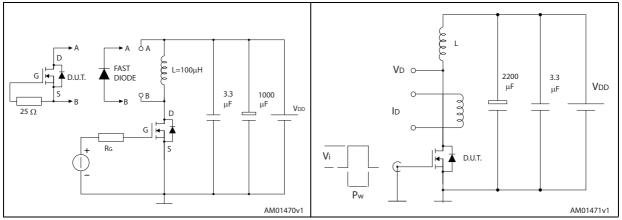
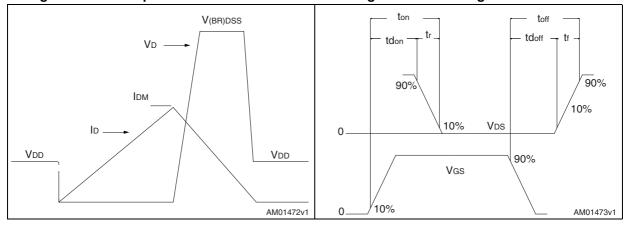


Figure 20. Unclamped inductive waveform

Figure 21. Switching time waveform



4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK[®] packages, depending on their level of environmental compliance. ECOPACK[®] specifications, grade definitions and product status are available at: *www.st.com*. ECOPACK[®] is an ST trademark.

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Table 9. DPAK (TO-252) type A mechanical data

D:	1450 51 217111 (1.0	mm	
Dim.	Min.	Тур.	Max.
А	2.20		2.40
A1	0.90		1.10
A2	0.03		0.23
b	0.64		0.90
b4	5.20		5.40
С	0.45		0.60
c2	0.48		0.60
D	6.00		6.20
D1		5.10	
E	6.40		6.60
E1		4.70	
е		2.28	
e1	4.40		4.60
Н	9.35		10.10
L	1.00		1.50
(L1)		2.80	
L2		0.80	
L4	0.60		1.00
R		0.20	
V2	0°		8°

Ε. THERMAL PAD c2 - E1 L2 Ď1 D Η A 1 <u>b(</u>2x) R С SEATING PLANE (L1) *V2* 0068772_M_type_

Figure 22. DPAK (TO-252) type A drawing

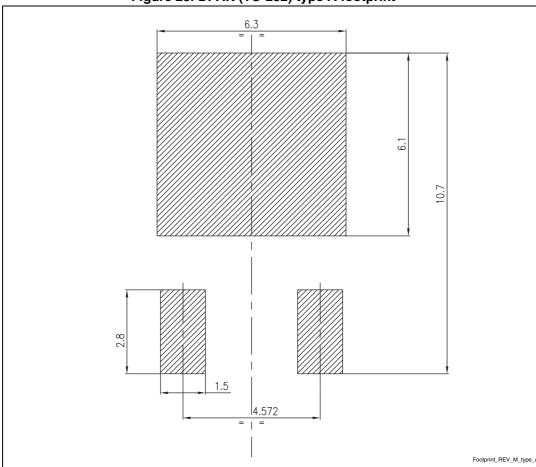


Figure 23. DPAK (TO-252) type A footprint ^(a)

a. All dimensions are in millimeters



Table 10. TO-220 type A mechanical data

D:	mm					
Dim.	Min.	Тур.	Max.			
Α	4.40		4.60			
b	0.61		0.88			
b1	1.14		1.70			
С	0.48		0.70			
D	15.25		15.75			
D1		1.27				
Е	10		10.40			
е	2.40		2.70			
e1	4.95		5.15			
F	1.23		1.32			
H1	6.20		6.60			
J1	2.40		2.72			
L	13		14			
L1	3.50		3.93			
L20		16.40				
L30		28.90				
ØP	3.75		3.85			
Q	2.65		2.95			

øΡ Ε H1 D <u>D1</u> L20 L30 b1(X3) b (X3) .e1__ 0015988_typeA_Rev_T

Figure 24. TO-220 type A drawing

Table 11. IPAK (TO-251) mechanical data

DIM	mm.			
	min.	typ.	max.	
Α	2.20		2.40	
A1	0.90		1.10	
b	0.64		0.90	
b2			0.95	
b4	5.20		5.40	
B5		0.30		
С	0.45		0.60	
c2	0.48		0.60	
D	6.00		6.20	
E	6.40		6.60	
е		2.28		
e1	4.40		4.60	
Н		16.10		
L	9.00		9.40	
L1	0.80		1.20	
L2		0.80	1.00	
V1		10°		

E-L2 D L1 *b2 (3x)* Н b (3x) V1 -*B5* -e1— 0068771_K

Figure 25. IPAK (TO-251) drawing

5 Packaging mechanical data

Table 12. DPAK (TO-252) tape and reel mechanical data

Tape				Reel		
Dim.	mm		Dim	mm		
	Min.	Max.	Dim.	Min.	Max.	
A0	6.8	7	Α		330	
В0	10.4	10.6	В	1.5		
B1		12.1	С	12.8	13.2	
D	1.5	1.6	D	20.2		
D1	1.5		G	16.4	18.4	
Е	1.65	1.85	N	50		
F	7.4	7.6	Т		22.4	
K0	2.55	2.75				
P0	3.9	4.1		Base qty.	2500	
P1	7.9	8.1		Bulk qty.	2500	
P2	1.9	2.1			•	
R	40					
Т	0.25	0.35				
W	15.7	16.3				

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Figure 26. Tape

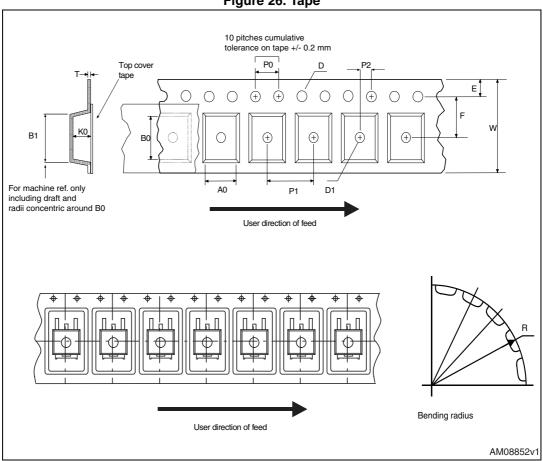
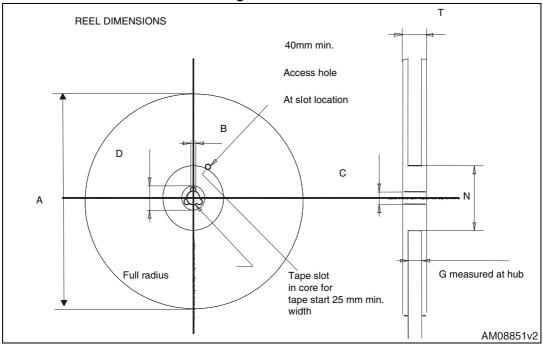


Figure 27. Reel



6 Revision history

Table 13. Document revision history

Date	Revision	Changes
17-Jul-2012	1	First release.
17-Oct-2012	2	Minor text changes in cover pageModified: title and I_D value in cover page
19-Dec-2012	3	 Minor text changes Added: IPAK package Updated: Section 4: Package mechanical data for IPAK
18-Mar-2013	4	- Modified: I _{AR} value on <i>Table 2</i> - Updated: <i>Section 4: Package mechanical data</i> only for DPAK package
09-Oct-2013	5	- The part number STF7N80K5 has been moved to a separate datasheet - Minor text changes

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